

# Enhancement of tunnel magnetoresistance in ferromagnetic single-electron transistors

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## Abstract

Magnetoresistance of ferromagnetic single-electron transistors (SETs) is known to increase at low temperatures. In this paper, we investigate systematically how the TMR enhancement changes as a function of the tunnel resistance  $R_T$  using Ni/Co/Ni-SETs. We find the enhancement almost independent of  $R_T$  as far as  $R_T > \sim 30$  k $\Omega$ , while it is small for devices with  $R_T < \sim 7$  k $\Omega$ . These results are not explained by the theories based on the higher-order tunneling.

*Key words:* tunnel magnetoresistance; single-electron transistor; ferromagnetic tunnel junction

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## 1. Introduction

The electron transport in ferromagnetic small tunnel junctions are attracting lots of interest. The electron has two natures, an electric charge  $e$  and a spin. The quantization of the charge causes the Coulomb blockade of conduction when  $kT < E_C$ , where  $E_C$  is the single-electron charging energy. The spin-polarized tunneling causes the tunnel magnetoresistance (TMR) effect, because the tunneling probability varies depending on the relative orientation of magnetizations in electrodes. The TMR is characterized by the TMR ratio defined as  $\gamma = (R_A - R_P)/R_P$ . Here,  $R_P$  ( $R_A$ ) denotes the resistance when the relative alignment of magnetizations in both electrodes is parallel (anti-parallel).

In 1997, Ono *et al.* reported that the TMR of a Ni/Co/Ni-SET was largely enhanced when it was cooled to the Coulomb blockade regime [1]. In their experiment, the TMR ratio that was about 4 % at 4.2 K grew up to 40 % at 20 mK, which is even larger than the maximum TMR ratio expected from spin polarized tunneling experiments. Similar enhancements of TMR had been observed in two-dimensional arrays

of a ferromagnetic tunnel junction [2]. Subsequently enhancement of the TMR was found in other systems including ferromagnetic granular films [3] and the small tunnel junctions [4]. The enhancement of TMR is not explained by the so-called orthodox theory of single-electron tunneling. Ono *et al.* presented an idea on the mechanism of the enhancement based on the quantum fluctuation of charge. Several theoretical papers based on the higher-order tunneling appeared and predicted the enhancement of TMR [5] [6] [7] [8]. However, the experimental investigations of the TMR enhancement have not been done systematically yet and the check of the theories remains insufficient.

In this paper, we fabricated ferromagnetic-SETs made of Ni and Co having various  $R_T$  ranging from 600  $\Omega$  to 3.3 M $\Omega$ , and investigated systematically how the TMR enhancement changes as a function of  $R_T$ .

## 2. Experiment

Ni/Co/Ni-SETs were fabricated by means of the electron-beam lithography followed by the double-angle evaporation. The metal films were 30 - 45 nm

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thick. We adopted two sorts of tunnel barriers,  $\text{Al}_2\text{O}_3$  and  $\text{NiO}$ . In the latter case,  $\text{NiO}$  barrier was formed by plasma oxidation of  $\text{Ni}$  electrode using  $\text{O}_2$ . (The suspended Ge mask was employed for such process because the Ge film was resistant to  $\text{O}_2$  plasma.) The size of tunnel junctions is about  $0.1\mu\text{m} \times 0.1\mu\text{m}$ . Electrical measurement was done at temperatures between 4.2 K and about 25 mK in magnetic fields up to 2 Tesla. We set the direction of the magnetic field parallel to the long axis of the island and the lead electrodes to realize the most distinct flip of the magnetization. The devices were characterized by the tunnel resistance  $R_T$  and the charging energy  $E_C$ . They were determined from the resistance at 4.2 K assuming both junctions were same, and from the offset voltage in the  $I$ - $V$  curve at the lowest temperature.

### 3. Results and Discussion

Figure 1 shows the temperature dependence of the TMR enhancement factor of various devices. Their tunnel resistance ranges between 600  $\Omega$  and 3.3 M $\Omega$ . Here, the enhancement factor means the TMR ratio at each temperature divided by that at 4.2 K. As not only the electron temperature  $T_e$  but also  $E_C$  is different among devices, we plot the data against  $E_C/kT_e$ , which is determined from the resistance using a theoretical temperature dependence of resistance by the orthodox theory. We find  $E_C/kT_e$  determined in this way is not in inverse proportion to the fridge temperature near the lowest temperature, which is probably because the electron temperature is raised by the external noise. We see in Fig.1 that the TMR ratio in various Ni/Co/Ni-SETs becomes large at low temperatures. We also note the devices with  $R_T$  larger than 22 k $\Omega$  have roughly similar temperature dependence of the enhancement. Namely,  $\gamma(T)/\gamma(4.2\text{K})$  increases noticeably above  $E_C/kT_e \approx 4$  and reaches about 10 at  $E_C/kT_e \approx 6$ . We find no systematic differences between, for example, the devices with  $R_T = 36$  k $\Omega$  and 3.3 M $\Omega$ . In Fig.1 we also plot the data for samples  $R_T$  smaller than  $R_Q = h/2e^2 = 12.9$  k $\Omega$ . The resistance of these samples increases slightly at low temperature, and the enhancement of TMR is not so evident. Obviously, the orthodox theory is not applicable to such devices, and the abscissa  $E_C/kT_e$  loses its original meaning. Nevertheless, interestingly enough, the plot in Fig.1 seems to suggest a kind of an universal curve of enhancement.

Theoretical models of TMR enhancement based on the higher-order tunneling have been proposed [5] [6] [7] [8]. If the enhancement relates to the higher-order tunneling, it is expected to be large for devices with  $R_T \approx R_Q$ , or at least it varies depending on  $R_T$ . Therefore, the results depicted in Fig.1 is not consistent with such

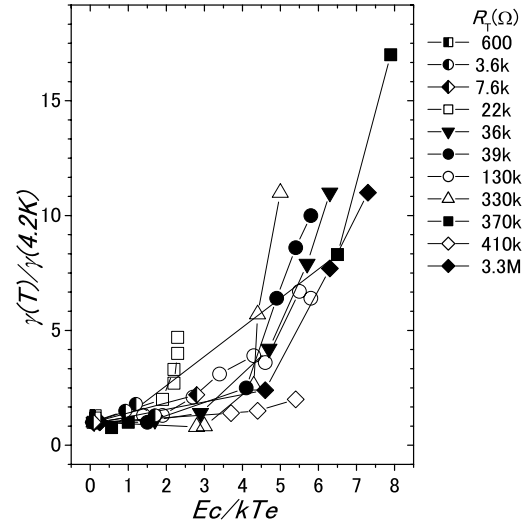


Fig. 1. Temperature dependence of TMR ratio

picture. Quantitatively, we have reported [6] that the estimation of enhancement using the renormalization of  $E_C$  [9] gave effects much smaller than experiment. It is also the case for the present experiment. The TMR enhancement estimated from the renormalization is 1.3 at most. Thus the theory based on the higher-order tunneling is not consistent with the experimental results. Wang *et al.* [8] performed Monte-Carlo simulation for strong tunneling and predicted very large enhancement of TMR for devices with  $R_T < R_Q$ . The temperature range where they predict such enhancement is, however, too low to check experimentally at present.

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